

# Microelectronics Working Group meeting

- General news from the CERN Foundry Service Team (10min)
- Single Event Latchup in 130nm circuits (10min)
- Stability of the TID response of 130 and 65nm technologies (5min)
- Total Ionising Dose response of 65nm MOSFETs irradiated to ultra-high doses (40min)
- Plans for the simulation of irradiated transistors in 65nm CMOS (5min)
- Plans for the evaluation of the TID effects in 40 and 28nm CMOS (5min)

Talks can be seen at:

<https://espace.cern.ch/asics-support/docs/layouts/15/start.aspx#/SitePages/Conferences.aspx>

if you do not have access, email a request to [foundry.services@cern.ch](mailto:foundry.services@cern.ch)